			E		n	E	2		5	1	C	
S	Е	М	T	С	0	Ν	D	U	С	Т	0	R

Die Datasheet

GA01PNS80-CAU

Silicon Carbide PiN Diode Chip

V _{RRM}	=	8000 V
I _F @ 25 °C	=	2 A

۰K

Features

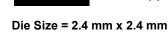
8 kV blocking

Advantages

• Reduced stacking

- 210 °C operating temperature
- Fast turn off characteristics
- Soft reverse recovery characteristics
- Ultra-Fast high temperature switching

• Reduced system complexity/Increased reliability





- Voltage Multiplier
- Ignition/Trigger Circuits
- Oil/Downhole
- Lighting
- Defense

Maximum Ratings at T_j = 210 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values	Unit
Repetitive peak reverse voltage	V _{RRM}		8	kV
Continuous forward current	I _F		2	А
RMS forward current	I _{F(RMS)}		1	Α
Operating and storage temperature	T _j , T _{stg}		-55 to 210	°C

Electrical Characteristics at T_i = 210 °C, unless otherwise specified

Parameter	Symphol	Conditions		Values		11
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Diode forward voltage	V _F	I _F = 2 A, T _j = 25 °C I _F = 2 A, T _j = 210 °C		6.1 4.3		V
Reverse current	I _R	V _R = 8 kV, T _j = 25 °C V _R = 8 kV, T _j = 175 °C		4 4		μA
Total reverse recovery charge	Q _{rr}	$I_{F} \le I_{F,MAX}$ $dI_{F}/dt = 70 \text{ A/}\mu \text{s}$ $V_{R} = 1000 \text{ V}$ $I_{F} = 1.5 \text{ A}$	/	558		nC
Switching time	t _s	$T_j = 210 \ ^{\circ}C$ $V_R = 1000 \ V_R = 1.5 \ A$	/	< 236		ns
Total capacitance	С	V _R = 1 V, f = 1 MHz, T _j = 25 °C V _R = 400 V, f = 1 MHz, T _j = 25 °C V _R = 1000 V, f = 1 MHz, T _i = 25 °C		26 5 4		pF
Total capacitive charge	Q _c	V _R = 1000 V, f = 1 MHz, T _j = 25 °C		5.4		nC



GA01PNS80-CAU

Figures:

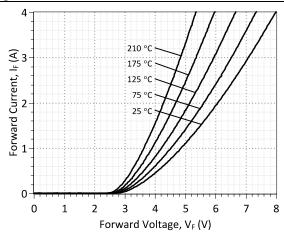


Figure 1: Typical Forward Characteristics

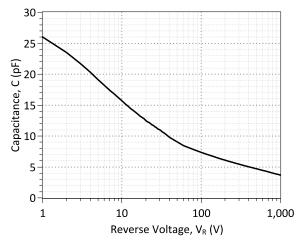
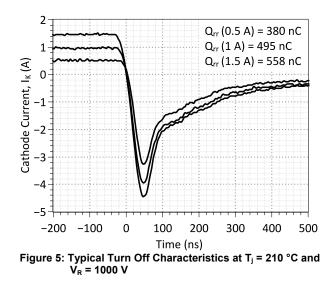


Figure 3: Typical Junction Capacitance vs Reverse Voltage Characteristics



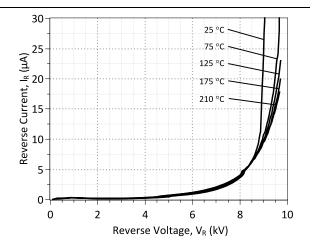
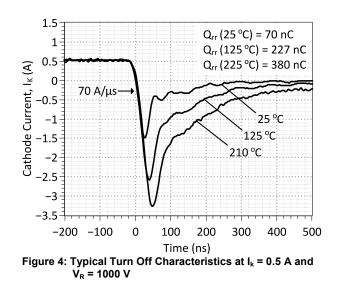
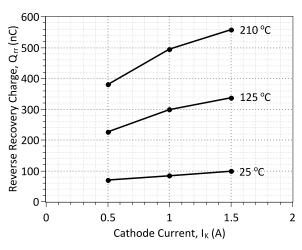
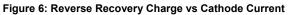


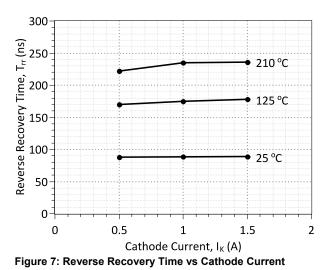
Figure 2: Typical Reverse Characteristics at 25C









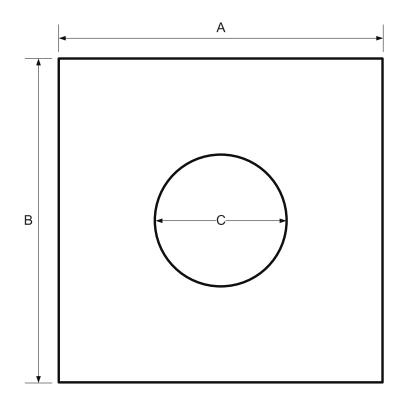




Mechanical Parameters

Die Dimensions	2.4 x 2.4	mm ²			
Anode pad size	Φ 0.98	mm			
Area total / active	5.76/0.75	mm²			
Die Thickness	450	μm			
Wafer Size	76.2	mm			
Flat Position	0	deg			
Die Frontside Passivation	Polyimide	Polyimide			
Anode Pad Metallization	400 nm Ni + 200 nm /	400 nm Ni + 200 nm Au			
Backside Cathode Metallization	400 nm Ni + 200 nm /	Чu			
Die Attach	Electrically conductive glue	Electrically conductive glue or solder			
Wire Bond	Au ≤ 26 µm	Au ≤ 26 μm			
Reject ink dot size	Φ ≥ 0.3 mm	Φ≥0.3 mm			
Decommonded storage on vironment	Store in original container, in d	ry nitrogen,			
Recommended storage environment	< 6 months at an ambient temper	< 6 months at an ambient temperature of 23 °C			

Chip Dimensions:



DIE	A [mm]	2.4		
DIE	B [mm]	2.4		
METAL	C [mm]	0.98		



Revision History							
Date Revision Comments Supersedes							
2015/04/30 2 Updated Electrical 0		Updated Electrical Characteristics					
2015/02/25	2015/02/25 1 Inserted Mechanical Parameters						
2013/11/27	0	Initial release					

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SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit_sic/baredie/pin/GA01PNS80-CAU_SPICE.pdf) into LTSPICE (version 4) software for simulation of the GA01PNS80-CAU device.

```
*
     MODEL OF GeneSiC Semiconductor Inc.
*
*
     $Revision: 1.1
                                 $
*
                                 $
     $Date: 30-APR-2015
*
     GeneSiC Semiconductor Inc.
*
*
     43670 Trade Center Place Ste. 155
*
     Dulles, VA 20166
*
     COPYRIGHT (C) 2013 GeneSiC Semiconductor Inc.
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*
* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
 Start of GA01PNS80-CAU SPICE Model
*
. MODEL GA01PNS80 D
+ IS
     9.2491e-015
          1.02512
+ RS
          3.3373
+ N
+ IKF
          0.00011784
          3.23
+ EG
         25
+ XTI
+ TRS1
         -0.0024
          2.7E-11
+ CJO
+ VJ
          2.304
          0.376
+ M
+ FC
          0.5
+ BV
          8000
+ IBV
          1.00E-03
+ VPK
          8000
+ IAVE
          1
+ TYPE
          SiC PiN
+ MFG
          GeneSiC Semi
*
* End of GA01PNS80-CAU SPICE Model
```